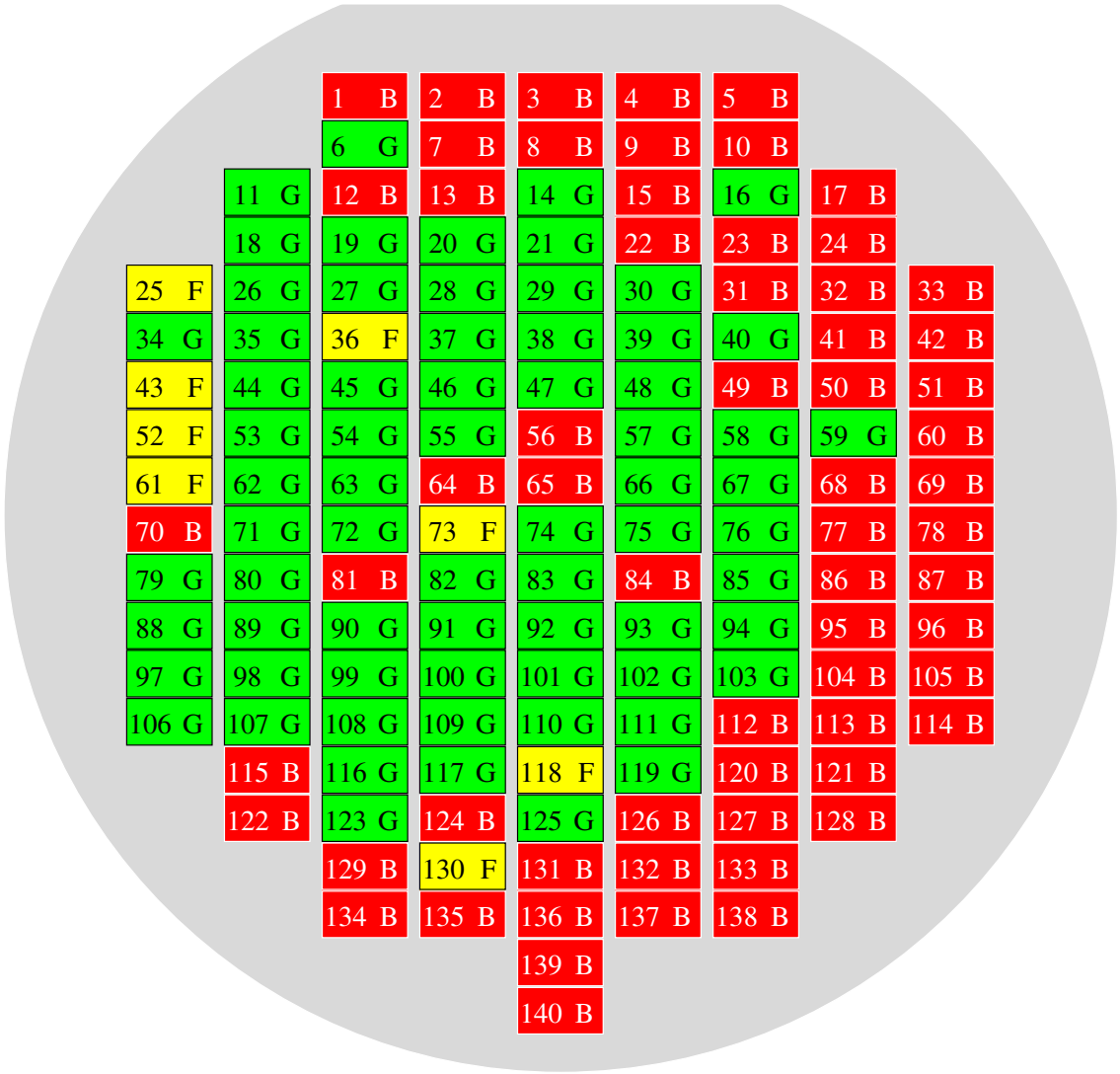
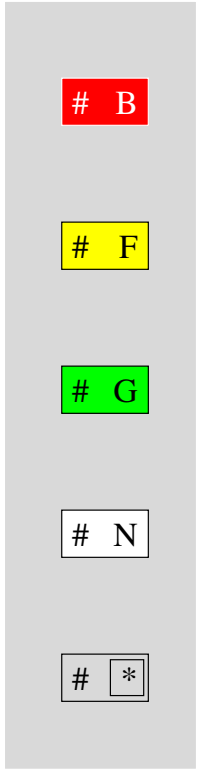
Die quality map for wafer 160 s/n: Y21316-08-07

Date: 06/23/99





Bad die

Fair die

Good die

No info

Manually tagged